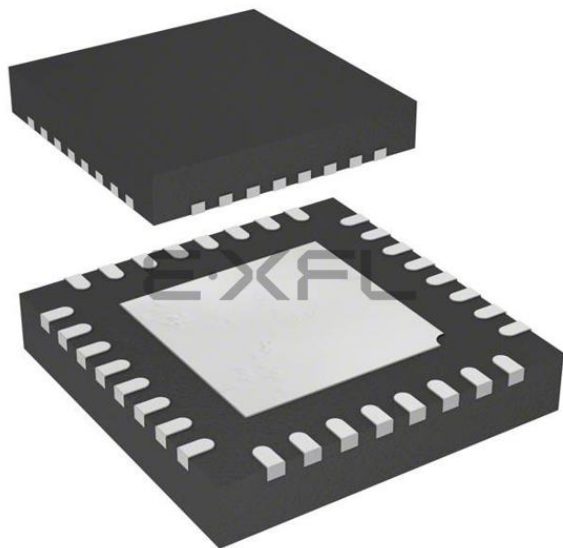




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Details

Product Status	Active
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I ² C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, IR, POR, PWM, WDT
Number of I/O	30
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 22x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-UFQFPN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8l151k6u6tr

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2 Description

The medium-density STM8L151x4/6 and STM8L152x4/6 devices are members of the STM8L ultra-low-power 8-bit family. The medium-density STM8L15x family operates from 1.8 V to 3.6 V (down to 1.65 V at power down) and is available in the -40 to +85 °C and -40 to +125 °C temperature ranges.

The medium-density STM8L15x ultra-low-power family features the enhanced STM8 CPU core providing increased processing power (up to 16 MIPS at 16 MHz) while maintaining the advantages of a CISC architecture with improved code density, a 24-bit linear addressing space and an optimized architecture for low power operations.

The family includes an integrated debug module with a hardware interface (SWIM) which allows non-intrusive In-Application debugging and ultra-fast Flash programming.

All medium-density STM8L15x microcontrollers feature embedded data EEPROM and low-power, low-voltage, single-supply program Flash memory.

They incorporate an extensive range of enhanced I/Os and peripherals.

The modular design of the peripheral set allows the same peripherals to be found in different ST microcontroller families including 32-bit families. This makes any transition to a different family very easy, and simplified even more by the use of a common set of development tools.

Six different packages are proposed from 28 to 48 pins. Depending on the device chosen, different sets of peripherals are included.

All STM8L ultra-low-power products are based on the same architecture with the same memory mapping and a coherent pinout.

3.19 Development support

Development tools

Development tools for the STM8 microcontrollers include:

- The STice emulation system offering tracing and code profiling
- The STVD high-level language debugger including C compiler, assembler and integrated development environment
- The STVP Flash programming software

The STM8 also comes with starter kits, evaluation boards and low-cost in-circuit debugging/programming tools.

Single wire data interface (SWIM) and debug module

The debug module with its single wire data interface (SWIM) permits non-intrusive real-time in-circuit debugging and fast memory programming.

The single-wire interface is used for direct access to the debugging module and memory programming. The interface can be activated in all device operation modes.

The non-intrusive debugging module features a performance close to a full-featured emulator. Beside memory and peripherals, CPU operation can also be monitored in real-time by means of shadow registers.

Bootloader

A bootloader is available to reprogram the Flash memory using the USART1 interface. The reference document for the bootloader is *UM0560: STM8 bootloader user manual*.

Figure 6. STM8L151G4, STM8L151G6 WLCSP28 package pinout

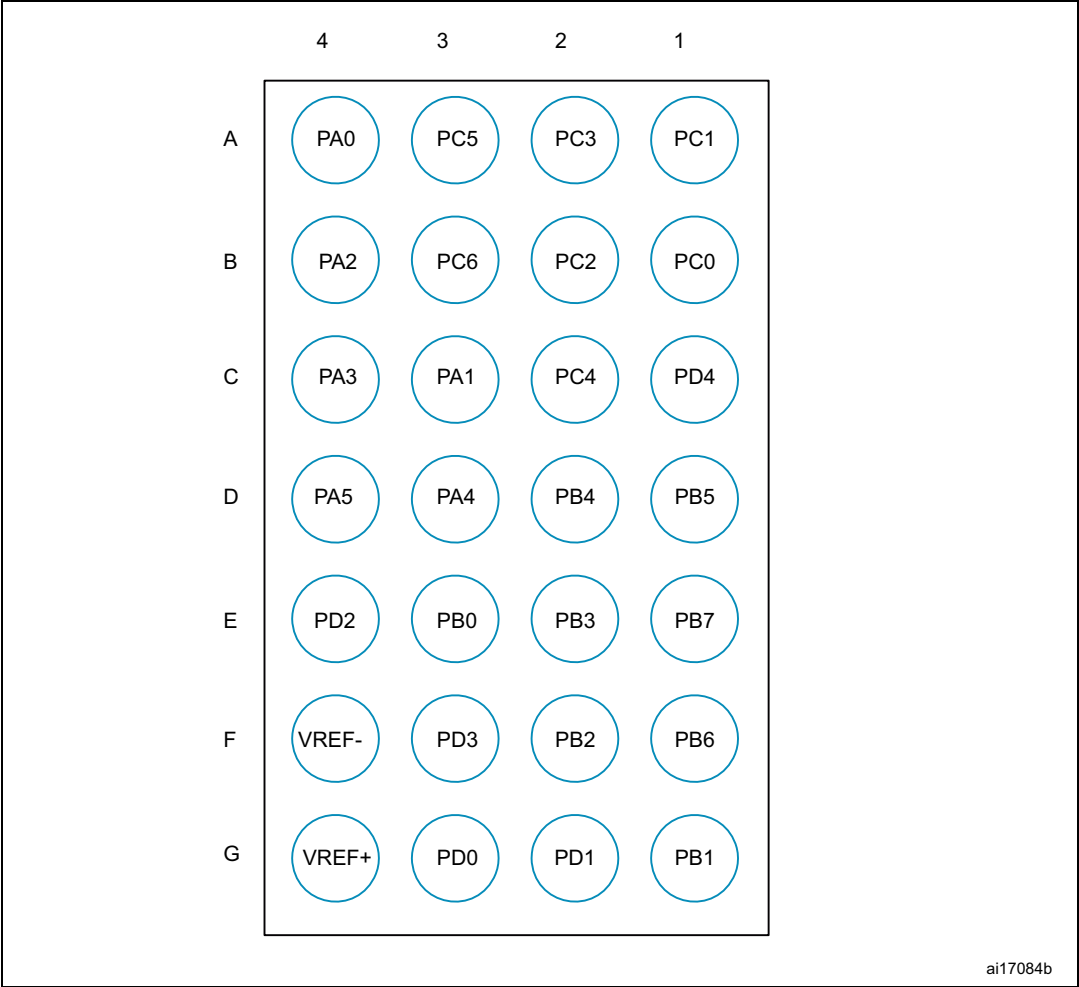


Figure 7. STM8L152C4, STM8L152C6 48-pin pinout (with LCD)

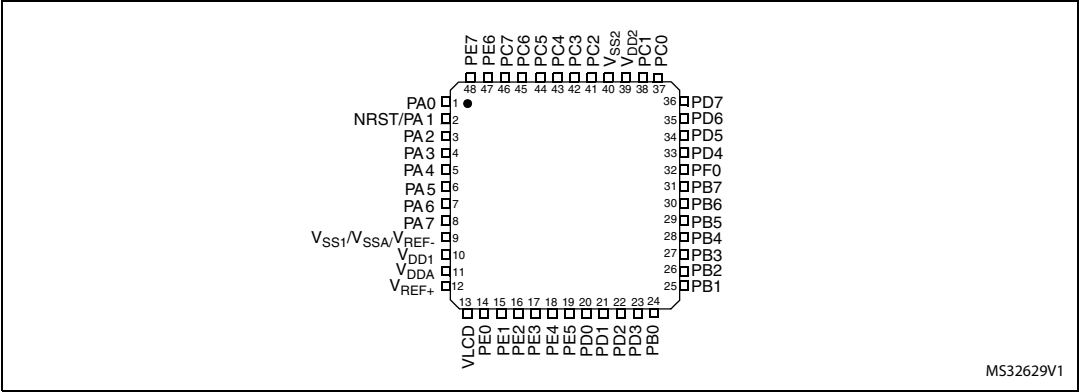
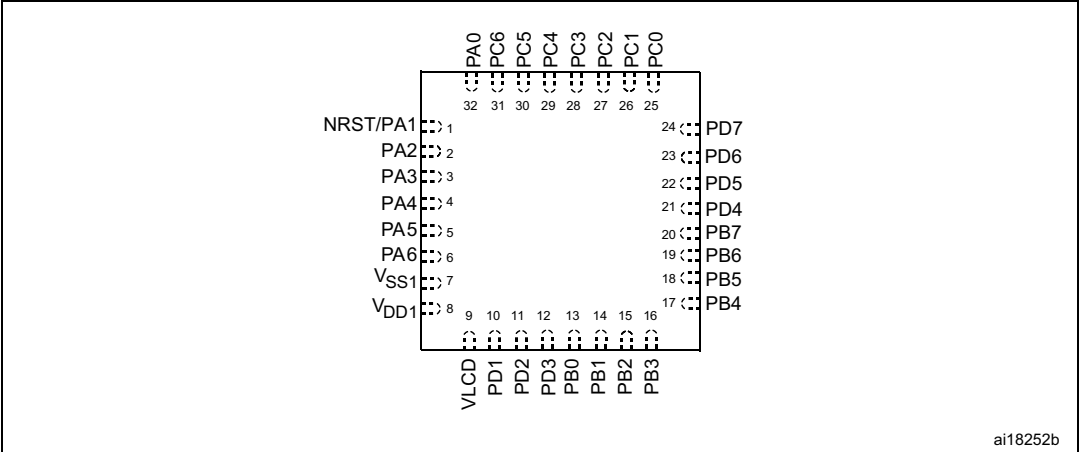


Figure 8. STM8L152K4, STM8L152K6 32-pin package pinout (with LCD)



1. Example given for the UFQFPN32 package. The pinout is the same for the LQFP32 package.

Table 8. I/O port hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 500A	Port C	PC_ODR	Port C data output latch register	0x00
0x00 500B		PC_IDR	Port C input pin value register	0xFF
0x00 500C		PC_DDR	Port C data direction register	0x00
0x00 500D		PC_CR1	Port C control register 1	0x00
0x00 500E		PC_CR2	Port C control register 2	0x00
0x00 500F	Port D	PD_ODR	Port D data output latch register	0x00
0x00 5010		PD_IDR	Port D input pin value register	0xFF
0x00 5011		PD_DDR	Port D data direction register	0x00
0x00 5012		PD_CR1	Port D control register 1	0x00
0x00 5013		PD_CR2	Port D control register 2	0x00
0x00 5014	Port E	PE_ODR	Port E data output latch register	0x00
0x00 5015		PE_IDR	Port E input pin value register	0xFF
0x00 5016		PE_DDR	Port E data direction register	0x00
0x00 5017		PE_CR1	Port E control register 1	0x00
0x00 5018		PE_CR2	Port E control register 2	0x00
0x00 5019	Port F	PF_ODR	Port F data output latch register	0x00
0x00 501A		PF_IDR	Port F input pin value register	0xFF
0x00 501B		PF_DDR	Port F data direction register	0x00
0x00 501C		PF_CR1	Port F control register 1	0x00
0x00 501D		PF_CR2	Port F control register 2	0x00

Table 9. General hardware register map

Address	Block	Register label	Register name	Reset status
0x00 501E to 0x00 5049	Reserved area (28 bytes)			
0x00 5050	Flash	FLASH_CR1	Flash control register 1	0x00
0x00 5051		FLASH_CR2	Flash control register 2	0x00
0x00 5052		FLASH_PUKR	Flash program memory unprotection key register	0x00
0x00 5053		FLASH_DUKR	Data EEPROM unprotection key register	0x00
0x00 5054		FLASH_IAPSR	Flash in-application programming status register	0x00

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 50D0 to 0x00 50D2	Reserved area (3 bytes)			
0x00 50D3	WWDG	WWDG_CR	WWDG control register	0x7F
0x00 50D4		WWDG_WR	WWDG window register	0x7F
0x00 50D5 to 0x00 50DF	Reserved area (11 bytes)			
0x00 50E0	IWDG	IWDG_KR	IWDG key register	0xFF
0x00 50E1		IWDG_PR	IWDG prescaler register	0x00
0x00 50E2		IWDG_RLR	IWDG reload register	0xFF
0x00 50E3 to 0x00 50EF	Reserved area (13 bytes)			
0x00 50F0	BEEP	BEEP_CSR1	BEEP control/status register 1	0x00
0x00 50F1 0x00 50F2		Reserved area (2 bytes)		
0x00 50F3		BEEP_CSR2	BEEP control/status register 2	0x1F
0x00 50F4 to 0x00 513F	Reserved area (76 bytes)			

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5200	SPI1	SPI1_CR1	SPI1 control register 1	0x00
0x00 5201		SPI1_CR2	SPI1 control register 2	0x00
0x00 5202		SPI1_ICR	SPI1 interrupt control register	0x00
0x00 5203		SPI1_SR	SPI1 status register	0x02
0x00 5204		SPI1_DR	SPI1 data register	0x00
0x00 5205		SPI1_CRCPR	SPI1 CRC polynomial register	0x07
0x00 5206		SPI1_RXCR	SPI1 Rx CRC register	0x00
0x00 5207		SPI1_TXCR	SPI1 Tx CRC register	0x00
0x00 5208 to 0x00 520F	Reserved area (8 bytes)			
0x00 5210	I2C1	I2C1_CR1	I2C1 control register 1	0x00
0x00 5211		I2C1_CR2	I2C1 control register 2	0x00
0x00 5212		I2C1_FREQR	I2C1 frequency register	0x00
0x00 5213		I2C1_OARL	I2C1 own address register low	0x00
0x00 5214		I2C1_OARH	I2C1 own address register high	0x00
0x00 5215		Reserved (1 byte)		
0x00 5216		I2C1_DR	I2C1 data register	0x00
0x00 5217		I2C1_SR1	I2C1 status register 1	0x00
0x00 5218		I2C1_SR2	I2C1 status register 2	0x00
0x00 5219		I2C1_SR3	I2C1 status register 3	0x0x
0x00 521A		I2C1_ITR	I2C1 interrupt control register	0x00
0x00 521B		I2C1_CCRL	I2C1 clock control register low	0x00
0x00 521C		I2C1_CCRH	I2C1 clock control register high	0x00
0x00 521D		I2C1_TRISER	I2C1 TRISE register	0x02
0x00 521E		I2C1_PECR	I2C1 packet error checking register	0x00
0x00 521F to 0x00 522F	Reserved area (17 bytes)			

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5430	RI	Reserved area (1 byte)		0x00
0x00 5431		RI_ICR1	Timer input capture routing register 1	0x00
0x00 5432		RI_ICR2	Timer input capture routing register 2	0x00
0x00 5433		RI_IOIR1	I/O input register 1	undefined
0x00 5434		RI_IOIR2	I/O input register 2	undefined
0x00 5435		RI_IOIR3	I/O input register 3	undefined
0x00 5436		RI_IOCMR1	I/O control mode register 1	0x00
0x00 5437		RI_IOCMR2	I/O control mode register 2	0x00
0x00 5438		RI_IOCMR3	I/O control mode register 3	0x00
0x00 5439		RI_IOSR1	I/O switch register 1	0x00
0x00 543A		RI_IOSR2	I/O switch register 2	0x00
0x00 543B		RI_IOSR3	I/O switch register 3	0x00
0x00 543C		RI_I OGCR	I/O group control register	0x3F
0x00 543D		RI_ASCR1	Analog switch register 1	0x00
0x00 543E		RI_ASCR2	Analog switch register 2	0x00
0x00 543F		RI_RCR	Resistor control register 1	0x00
0x00 5440	COMP	COMP_CSR1	Comparator control and status register 1	0x00
0x00 5441		COMP_CSR2	Comparator control and status register 2	0x00
0x00 5442		COMP_CSR3	Comparator control and status register 3	0x00
0x00 5443		COMP_CSR4	Comparator control and status register 4	0x00
0x00 5444		COMP_CSR5	Comparator control and status register 5	0x00

1. These registers are not impacted by a system reset. They are reset at power-on.

8 Unique ID

STM8 devices feature a 96-bit unique device identifier which provides a reference number that is unique for any device and in any context. The 96 bits of the identifier can never be altered by the user.

The unique device identifier can be read in single bytes and may then be concatenated using a custom algorithm.

The unique device identifier is ideally suited:

- For use as serial numbers
- For use as security keys to increase the code security in the program memory while using and combining this unique ID with software cryptographic primitives and protocols before programming the internal memory.
- To activate secure boot processes

Table 14. Unique ID registers (96 bits)

Address	Content description	Unique ID bits							
		7	6	5	4	3	2	1	0
0x4926	X co-ordinate on the wafer	U_ID[7:0]							
0x4927		U_ID[15:8]							
0x4928	Y co-ordinate on the wafer	U_ID[23:16]							
0x4929		U_ID[31:24]							
0x492A	Wafer number	U_ID[39:32]							
0x492B	Lot number	U_ID[47:40]							
0x492C		U_ID[55:48]							
0x492D		U_ID[63:56]							
0x492E		U_ID[71:64]							
0x492F		U_ID[79:72]							
0x4930		U_ID[87:80]							
0x4931		U_ID[95:88]							

9.3.2 Embedded reset and power control block characteristics

Table 19. Embedded reset and power control block characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
t_{VDD}	V_{DD} rise time rate	BOR detector enabled	0 ⁽¹⁾	-	∞ ⁽¹⁾	$\mu\text{s/V}$
	V_{DD} fall time rate	BOR detector enabled	20 ⁽¹⁾	-	∞ ⁽¹⁾	
t_{TEMP}	Reset release delay	V_{DD} rising BOR detector enabled	-	3	-	ms
		V_{DD} rising BOR detector disabled	-	1	-	
V_{PDR}	Power-down reset threshold	Falling edge	1.30 ⁽²⁾	1.50	1.65	V
V_{BOR0}	Brown-out reset threshold 0 (BOR_TH[2:0]=000)	Falling edge	1.67	1.70	1.74	V
		Rising edge	1.69	1.75	1.80	
V_{BOR1}	Brown-out reset threshold 1 (BOR_TH[2:0]=001)	Falling edge	1.87	1.93	1.97	
		Rising edge	1.96	2.04	2.07	
V_{BOR2}	Brown-out reset threshold 2 (BOR_TH[2:0]=010)	Falling edge	2.22	2.3	2.35	
		Rising edge	2.31	2.41	2.44	
V_{BOR3}	Brown-out reset threshold 3 (BOR_TH[2:0]=011)	Falling edge	2.45	2.55	2.60	
		Rising edge	2.54	2.66	2.7	
V_{BOR4}	Brown-out reset threshold 4 (BOR_TH[2:0]=100)	Falling edge	2.68	2.80	2.85	
		Rising edge	2.78	2.90	2.95	
V_{PVD0}	PVD threshold 0	Falling edge	1.80	1.84	1.88	V
		Rising edge	1.88	1.94	1.99	
V_{PVD1}	PVD threshold 1	Falling edge	1.98	2.04	2.09	
		Rising edge	2.08	2.14	2.18	
V_{PVD2}	PVD threshold 2	Falling edge	2.2	2.24	2.28	
		Rising edge	2.28	2.34	2.38	
V_{PVD3}	PVD threshold 3	Falling edge	2.39	2.44	2.48	
		Rising edge	2.47	2.54	2.58	
V_{PVD4}	PVD threshold 4	Falling edge	2.57	2.64	2.69	
		Rising edge	2.68	2.74	2.79	
V_{PVD5}	PVD threshold 5	Falling edge	2.77	2.83	2.88	
		Rising edge	2.87	2.94	2.99	
V_{PVD6}	PVD threshold 6	Falling edge	2.97	3.05	3.09	
		Rising edge	3.08	3.15	3.20	

Current consumption of on-chip peripherals

Table 27. Peripheral current consumption

Symbol	Parameter		Typ. $V_{DD} = 3.0\text{ V}$	Unit
$I_{DD}(TIM1)$	TIM1 supply current ⁽¹⁾		13	$\mu\text{A/MHz}$
$I_{DD}(TIM2)$	TIM2 supply current ⁽¹⁾		8	
$I_{DD}(TIM3)$	TIM3 supply current ⁽¹⁾		8	
$I_{DD}(TIM4)$	TIM4 timer supply current ⁽¹⁾		3	
$I_{DD}(USART1)$	USART1 supply current ⁽²⁾		6	
$I_{DD}(SPI1)$	SPI1 supply current ⁽²⁾		3	
$I_{DD}(I2C1)$	I ² C1 supply current ⁽²⁾		5	
$I_{DD}(DMA1)$	DMA1 supply current ⁽²⁾		3	
$I_{DD}(WWDG)$	WWDG supply current ⁽²⁾		2	
$I_{DD}(ALL)$	Peripherals ON ⁽³⁾		44	$\mu\text{A/MHz}$
$I_{DD}(ADC1)$	ADC1 supply current ⁽⁴⁾		1500	μA
$I_{DD}(DAC)$	DAC supply current ⁽⁵⁾		370	μA
$I_{DD}(COMP1)$	Comparator 1 supply current ⁽⁶⁾		0.160	μA
$I_{DD}(COMP2)$	Comparator 2 supply current ⁽⁶⁾	Slow mode	2	
		Fast mode	5	
$I_{DD}(PVD/BOR)$	Power voltage detector and brownout Reset unit supply current ⁽⁷⁾		2.6	
$I_{DD}(BOR)$	Brownout Reset unit supply current ⁽⁷⁾		2.4	
$I_{DD}(IDWDG)$	Independent watchdog supply current	including LSI supply current	0.45	
		excluding LSI supply current	0.05	

1. Data based on a differential I_{DD} measurement between all peripherals OFF and a timer counter running at 16 MHz. The CPU is in Wait mode in both cases. No IC/OC programmed, no I/O pins toggling. Not tested in production.
2. Data based on a differential I_{DD} measurement between the on-chip peripheral in reset configuration and not clocked and the on-chip peripheral when clocked and not kept under reset. The CPU is in Wait mode in both cases. No I/O pins toggling. Not tested in production.
3. Peripherals listed above the $I_{DD}(ALL)$ parameter ON: TIM1, TIM2, TIM3, TIM4, USART1, SPI1, I2C1, DMA1, WWDG.
4. Data based on a differential I_{DD} measurement between ADC in reset configuration and continuous ADC conversion.
5. Data based on a differential I_{DD} measurement between DAC in reset configuration and continuous DAC conversion of $V_{DD}/2$. Floating DAC output.
6. Data based on a differential I_{DD} measurement between COMP1 or COMP2 in reset configuration and COMP1 or COMP2 enabled with static inputs. Supply current of internal reference voltage excluded.
7. Including supply current of internal reference voltage.

9.3.5 Memory characteristics

T_A = -40 to 125 °C unless otherwise specified.

Table 35. RAM and hardware registers

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{RM}	Data retention mode ⁽¹⁾	Halt mode (or Reset)	1.65	-	-	V

1. Minimum supply voltage without losing data stored in RAM (in Halt mode or under Reset) or in hardware registers (only in Halt mode). Guaranteed by characterization, not tested in production.

Flash memory

Table 36. Flash program and data EEPROM memory

Symbol	Parameter	Conditions	Min	Typ	Max ⁽¹⁾	Unit
V_{DD}	Operating voltage (all modes, read/write/erase)	$f_{SYSCLK} = 16 \text{ MHz}$	1.65	-	3.6	V
t_{prog}	Programming time for 1 or 64 bytes (block) erase/write cycles (on programmed byte)	-	-	6	-	ms
	Programming time for 1 to 64 bytes (block) write cycles (on erased byte)	-	-	3	-	ms
I_{prog}	Programming/ erasing consumption	$T_A = +25 \text{ °C}$, $V_{DD} = 3.0 \text{ V}$	-	0.7	-	mA
		$T_A = +25 \text{ °C}$, $V_{DD} = 1.8 \text{ V}$	-	0.7	-	
$t_{RET}^{(2)}$	Data retention (program memory) after 10000 erase/write cycles at $T_A = -40$ to $+85 \text{ °C}$ (6 suffix)	$T_{RET} = +85 \text{ °C}$	30 ⁽¹⁾	-	-	years
	Data retention (program memory) after 10000 erase/write cycles at $T_A = -40$ to $+125 \text{ °C}$ (3 suffix)	$T_{RET} = +125 \text{ °C}$	5 ⁽¹⁾	-	-	
	Data retention (data memory) after 300000 erase/write cycles at $T_A = -40$ to $+85 \text{ °C}$ (6 suffix)	$T_{RET} = +85 \text{ °C}$	30 ⁽¹⁾	-	-	
	Data retention (data memory) after 300000 erase/write cycles at $T_A = -40$ to $+125 \text{ °C}$ (3 suffix)	$T_{RET} = +125 \text{ °C}$	5 ⁽¹⁾	-	-	
$N_{RW}^{(3)}$	Erase/write cycles (program memory)	$T_A = -40$ to $+85 \text{ °C}$ (6 suffix), $T_A = -40$ to $+125 \text{ °C}$ (3 suffix)	10 ⁽¹⁾	-	-	kcycles
	Erase/write cycles (data memory)		300 ⁽¹⁾ (4)	-	-	

1. Data based on characterization results.

2. Conforming to JEDEC JESD22a117

3. The physical granularity of the memory is 4 bytes, so cycling is performed on 4 bytes even when a write/erase operation addresses a single byte.

4. Data based on characterization performed on the whole data memory.

9.3.8 Communication interfaces

SPI1 - Serial peripheral interface

Unless otherwise specified, the parameters given in [Table 43](#) are derived from tests performed under ambient temperature, f_{SYSCLK} frequency and V_{DD} supply voltage conditions summarized in [Section 9.3.1](#). Refer to I/O port characteristics for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO).

Table 43. SPI1 characteristics

Symbol	Parameter	Conditions ⁽¹⁾	Min	Max	Unit
f_{SCK} $1/t_{\text{c(SCK)}}$	SPI1 clock frequency	Master mode	0	8	MHz
		Slave mode	0	8	
$t_{\text{r(SCK)}}$ $t_{\text{f(SCK)}}$	SPI1 clock rise and fall time	Capacitive load: C = 30 pF	-	30	ns
$t_{\text{su(NSS)}}^{(2)}$	NSS setup time	Slave mode	$4 \times 1/f_{\text{SYSCLK}}$	-	
$t_{\text{h(NSS)}}^{(2)}$	NSS hold time	Slave mode	80	-	
$t_{\text{w(SCKH)}}^{(2)}$ $t_{\text{w(SCKL)}}^{(2)}$	SCK high and low time	Master mode, $f_{\text{MASTER}} = 8 \text{ MHz}$, $f_{\text{SCK}} = 4 \text{ MHz}$	105	145	
$t_{\text{su(MI)}}^{(2)}$ $t_{\text{su(SI)}}^{(2)}$	Data input setup time	Master mode	30	-	
		Slave mode	3	-	
$t_{\text{h(MI)}}^{(2)}$ $t_{\text{h(SI)}}^{(2)}$	Data input hold time	Master mode	15	-	
		Slave mode	0	-	
$t_{\text{a(SO)}}^{(2)(3)}$	Data output access time	Slave mode	-	$3 \times 1/f_{\text{SYSCLK}}$	
$t_{\text{dis(SO)}}^{(2)(4)}$	Data output disable time	Slave mode	30	-	
$t_{\text{v(SO)}}^{(2)}$	Data output valid time	Slave mode (after enable edge)	-	60	
$t_{\text{v(MO)}}^{(2)}$	Data output valid time	Master mode (after enable edge)	-	20	
$t_{\text{h(SO)}}^{(2)}$	Data output hold time	Slave mode (after enable edge)	15	-	
$t_{\text{h(MO)}}^{(2)}$		Master mode (after enable edge)	1	-	

- Parameters are given by selecting 10 MHz I/O output frequency.
- Values based on design simulation and/or characterization results.
- Min time is for the minimum time to drive the output and max time is for the maximum time to validate the data.
- Min time is for the minimum time to invalidate the output and max time is for the maximum time to put the data in Hi-Z.

In the following table, data is guaranteed by design, not tested in production.

Table 49. Comparator 2 characteristics

Symbol	Parameter	Conditions	Min	Typ	Max ⁽¹⁾	Unit
V_{DDA}	Analog supply voltage	-	1.65	-	3.6	V
T_A	Temperature range	-	-40	-	125	°C
V_{IN}	Comparator 2 input voltage range	-	0	-	V_{DDA}	V
t_{START}	Comparator startup time	Fast mode	-	15	20	μs
		Slow mode	-	20	25	
$t_{d\ slow}$	Propagation delay in slow mode ⁽²⁾	$1.65\ V \leq V_{DDA} \leq 2.7\ V$	-	1.8	3.5	
		$2.7\ V \leq V_{DDA} \leq 3.6\ V$	-	2.5	6	
$t_{d\ fast}$	Propagation delay in fast mode ⁽²⁾	$1.65\ V \leq V_{DDA} \leq 2.7\ V$	-	0.8	2	
		$2.7\ V \leq V_{DDA} \leq 3.6\ V$	-	1.2	4	
V_{offset}	Comparator offset error	-	-	± 4	± 20	mV
I_{COMP2}	Current consumption ⁽³⁾	Fast mode	-	3.5	5	μA
		Slow mode	-	0.5	2	

1. Based on characterization.
2. The delay is characterized for 100 mV input step with 10 mV overdrive on the inverting input, the non-inverting input set to the reference.
3. Comparator consumption only. Internal reference voltage not included.

In the following table, data is based on characterization results, not tested in production.

Table 51. DAC accuracy

Symbol	Parameter	Conditions	Typ	Max	Unit
DNL	Differential non linearity ⁽¹⁾	$R_L \geq 5 \text{ k}\Omega$, $C_L \leq 50 \text{ pF}$ DACOUT buffer ON ⁽²⁾	1.5	3	12-bit LSB
		No load DACOUT buffer OFF	1.5	3	
INL	Integral non linearity ⁽³⁾	$R_L \geq 5 \text{ k}\Omega$, $C_L \leq 50 \text{ pF}$ DACOUT buffer ON ⁽²⁾	2	4	
		No load DACOUT buffer OFF	2	4	
Offset	Offset error ⁽⁴⁾	$R_L \geq 5 \text{ k}\Omega$, $C_L \leq 50 \text{ pF}$ DACOUT buffer ON ⁽²⁾	± 10	± 25	
		No load DACOUT buffer OFF	± 5	± 8	
Offset1	Offset error at Code 1 ⁽⁵⁾	DACOUT buffer OFF	± 1.5	± 5	
Gain error	Gain error ⁽⁶⁾	$R_L \geq 5 \text{ k}\Omega$, $C_L \leq 50 \text{ pF}$ DACOUT buffer ON ⁽²⁾	+0.1/-0.2	+0.2/-0.5	%
		No load DACOUT buffer OFF	+0/-0.2	+0/-0.4	
TUE	Total unadjusted error	$R_L \geq 5 \text{ k}\Omega$, $C_L \leq 50 \text{ pF}$ DACOUT buffer ON ⁽²⁾	12	30	12-bit LSB
		No load DACOUT buffer OFF	8	12	

1. Difference between two consecutive codes - 1 LSB.
2. For 48-pin packages only. For 28-pin and 32-pin packages, DAC output buffer must be kept off and no load must be applied.
3. Difference between measured value at Code i and the value at Code i on a line drawn between Code 0 and last Code 1023.
4. Difference between the value measured at Code (0x800) and the ideal value = $V_{REF+}/2$.
5. Difference between the value measured at Code (0x001) and the ideal value.
6. Difference between the ideal slope of the transfer function and the measured slope computed from Code 0x000 and 0xFFFF when buffer is ON, and from Code giving 0.2 V and ($V_{DDA} - 0.2$) V when buffer is OFF.

In the following table, data is guaranteed by design, not tested in production.

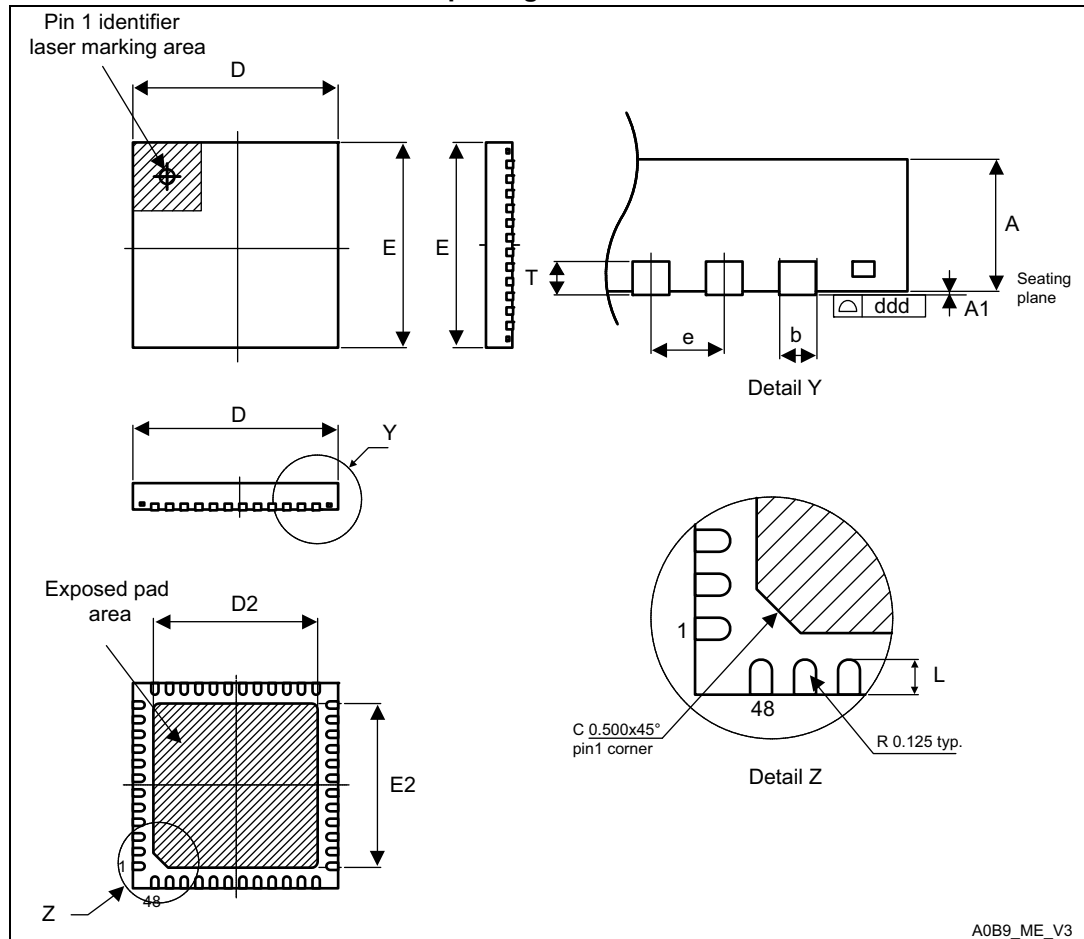
Table 52. DAC output on PB4-PB5-PB6⁽¹⁾

Symbol	Parameter	Conditions	Max	Unit
R_{int}	Internal resistance between DAC output and PB4-PB5-PB6 output	$2.7 \text{ V} < V_{DD} < 3.6 \text{ V}$	1.4	k Ω
		$2.4 \text{ V} < V_{DD} < 3.6 \text{ V}$	1.6	
		$2.0 \text{ V} < V_{DD} < 3.6 \text{ V}$	3.2	
		$1.8 \text{ V} < V_{DD} < 3.6 \text{ V}$	8.2	

1. 32 or 28-pin packages only. The DAC channel can be routed either on PB4, PB5 or PB6 using the routing interface I/O switch registers.

10.3 UFQFPN48 package information

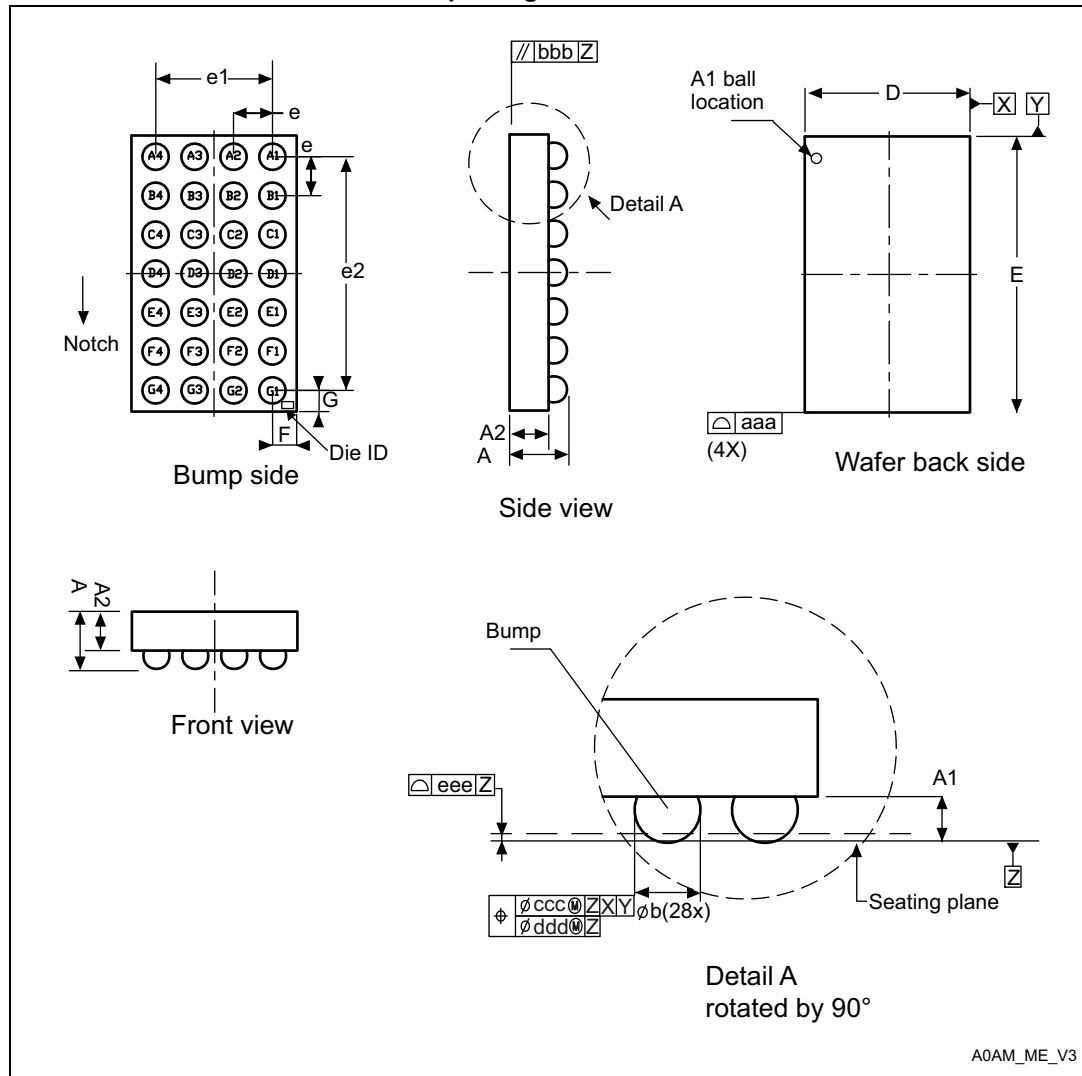
Figure 46. UFQFPN48 - 48-lead, 7 x 7 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package outline



1. Drawing is not to scale.
2. All leads/pads should also be soldered to the PCB to improve the lead/pad solder joint life.
3. There is an exposed die pad on the underside of the UFQFPN package. It is recommended to connect and solder this back-side pad to PCB ground.

10.7 WLCSP28 package information

Figure 58. WLCSP28 - 28-pin, 1.703 x 2.841 mm, 0.4 mm pitch wafer level chip scale package outline



1. Drawing is not to scale.